Lattice Semiconductor Corporation - ISPLSI 5256VE-125LT128I Datasheet

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Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

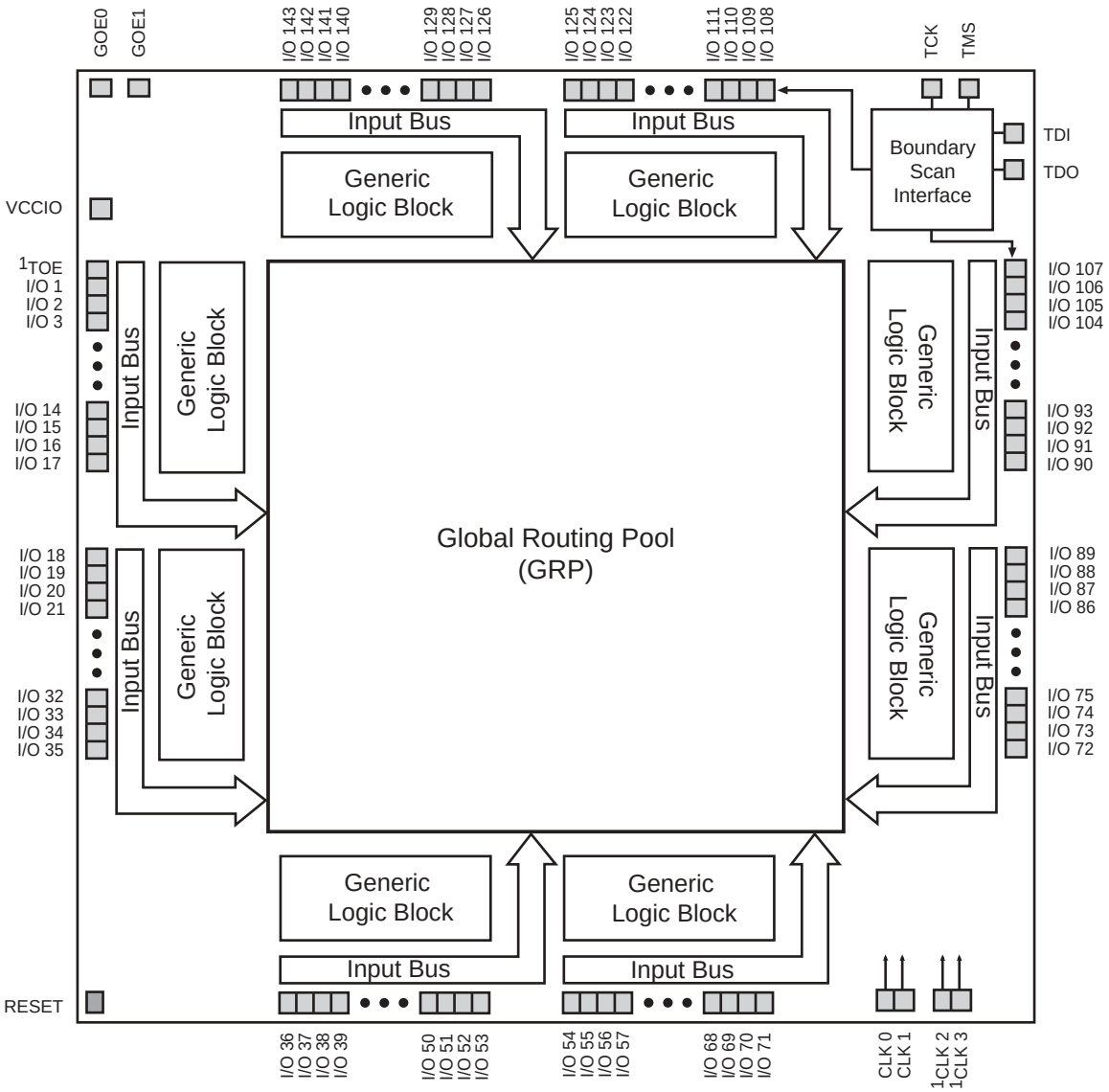
Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	7.5 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	8
Number of Macrocells	256
Number of Gates	12000
Number of I/O	96
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	128-LQFP
Supplier Device Package	128-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/isplsi-5256ve-125lt128i

Functional Block Diagram

Figure 1. ispLSI 5256VE Functional Block Diagram (144-I/O Option)



1. CLK2, CLK3 and TOE signals are shared with I/O signals. Use the table below to determine which I/O is shared by package type.

Package Type	Multplexed Signals		
100 TQFP	1/O 44 / CLK2	I/O 49 / CLK 3	I/O 0 / TOE
128 TQFP	I/O 59 / CLK2	I/O 65 / CLK3	I/O 0 / TOE
256 fpBGA	I/O 119 / CLK2	I/O 131 / CLK3	I/O 0 / TOE
272 BGA	I/O 119 / CLK2	I/O 131 / CLK3	I/O 0 / TOE

ispLSI 5000VE Description (Continued)

The 32 registered macrocells in the GLB are driven by the 32 outputs from the PTSA or the PTSA bypass. Each macrocell contains a programmable XOR gate, a programmable register/latch and the necessary clocks and control logic to allow combinatorial or registered operation. The macrocells each have two outputs, combinatorial and registered. This dual output capability from the macrocell allows efficient use of the hardware resources. One output can be a registered function for example, while the other output can be an unrelated combinatorial function. A direct register input from the I/O pad facilitates efficient use of this feature to construct high-speed input registers.

Macrocell registers can be clocked from one of several global or product term clocks available on the device. A global and product term clock enable is also available to each register, eliminating the need to gate the clock to the macrocell registers. Reset for the macrocell register is provided from the global signal, its polarity is user-selectable. The macrocell register can be programmed to operate as a D-type register or a D-type latch.

The 32 outputs from the GLB can drive both the Global Routing Pool and the device I/O cells. The Global Routing Pool contains one input from each macrocell output and one input from each I/O pin.

The input buffer threshold has programmable TTL/3.3V/2.5V compatible levels. The output driver can source 4mA and sink 8mA in 3.3V mode. The output drivers have a separate VCCIO reference input which is independent of the main VCC supply for the device. This feature allows individual output drivers to drive either 3.3V (from the device VCC) or 2.5V (from the VCCIO pin) output levels while the device logic and the output current drive are powered from device supply (VCC). The output drivers also provide individually programmable edge rates and open drain capability. A programmable pullup resistor is provided to tie off unused inputs. Additionally, a programmable bus-hold latch is available to hold tristate outputs in their last valid state until the bus is driven again by some device.

The ispLSI 5000VE Family features 3.3V, non-volatile in-system programmability for both the logic and the interconnect structures, providing the means to develop truly reconfigurable systems. Programming is achieved through the industry standard IEEE 1149.1-compliant Boundary Scan interface. Boundary Scan test is also supported through the same interface.

An enhanced, multiple cell security scheme is provided that prevents reading of the JEDEC programming file when secured. After the device has been secured using this mechanism, the only way to clear the security is to execute a bulk-erase instruction.

ispLSI 5000VE Family Members

The ispLSI 5000VE Family ranges from 128 macrocells to 512 macrocells and operates from a 3.3V power supply. All family members will be available with multiple package options. The ispLSI 5000VE Family device matrix showing the various bondout options is shown in the table below.

The interconnect structure (GRP) is very similar to Lattice's existing ispLSI 1000, 2000 and 3000 families, but with an enhanced interconnect structure for optimal pin locking and logic routing. This eliminates the need for registered I/O cells or an Output Routing Pool.

The ispLSI 5000VE encompasses the innovative features of the ispLSI 5000VA family with several enhancements. The macrocell is optimized and the T-type flip flop option is removed. To improve the efficiency of design fits, the Product Term Reset Logic is simplified and the polarity option as well as the Global Preset function are removed. The programmable output-delay feature (skew option) is also removed. As a result, the ispLSI 5000VE is not JEDEC compatible with the ispLSI 5000VA. ispLSI 5000VA and 5000VE pinouts may differ in the same package, however all programming and power/ground pins are located in the same locations.

Table 1. ispLSI 5000VE Family

				Package Type				
Device	**GLBs**	**Macrocells**	**100 TQFP**	**128 TQFP**	**256 fpBGA**	**272 BGA**	**388 fpBGA**	**388 BGA**
ispLSI 5128VE	4	128	—	96 I/O	—	—	—	—
ispLSI 5256VE	8	256	72 I/O	96 I/O	144 I/O	144 I/O	—	—
ispLSI 5384VE	12	384	—	—	192 I/O	192 I/O	—	—
ispLSI 5512VE	16	512	—	—	192 I/O	192 I/O	256 I/O	256 I/O

Figure 2. ispLSI 5256VE Block Diagram (144 I/O Version)

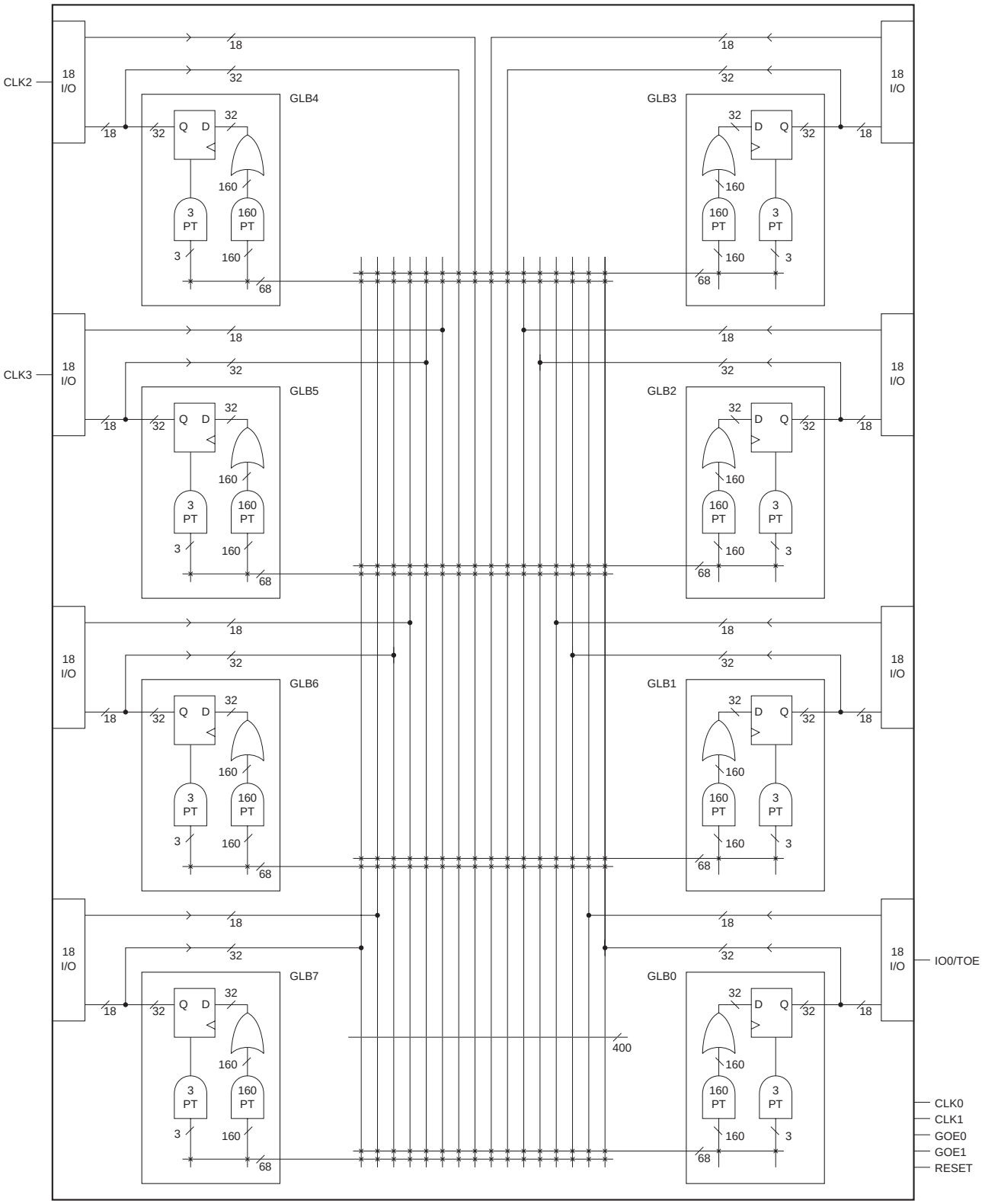


Figure 3. ispLSI 5000VE Generic Logic Block (GLB)

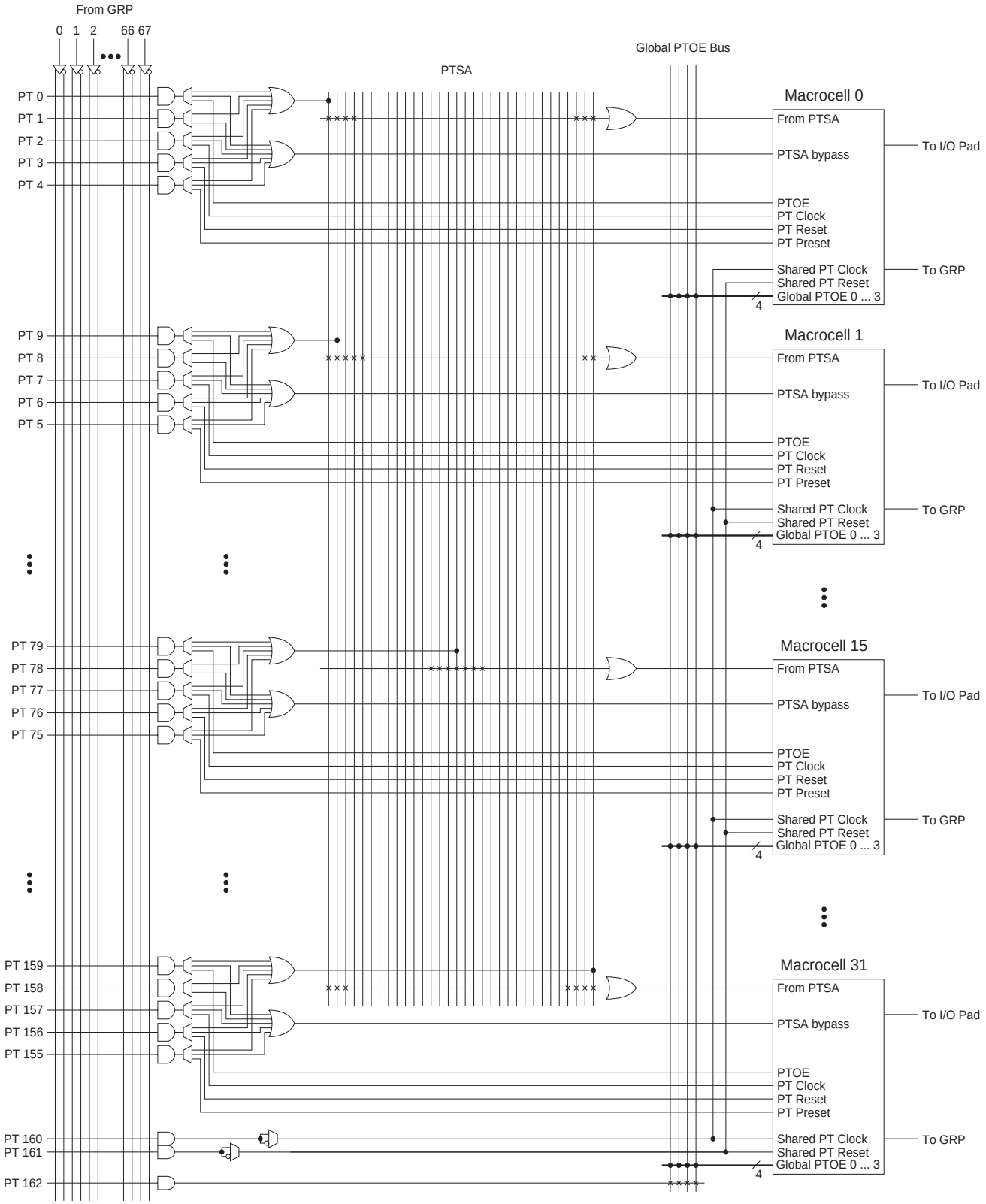
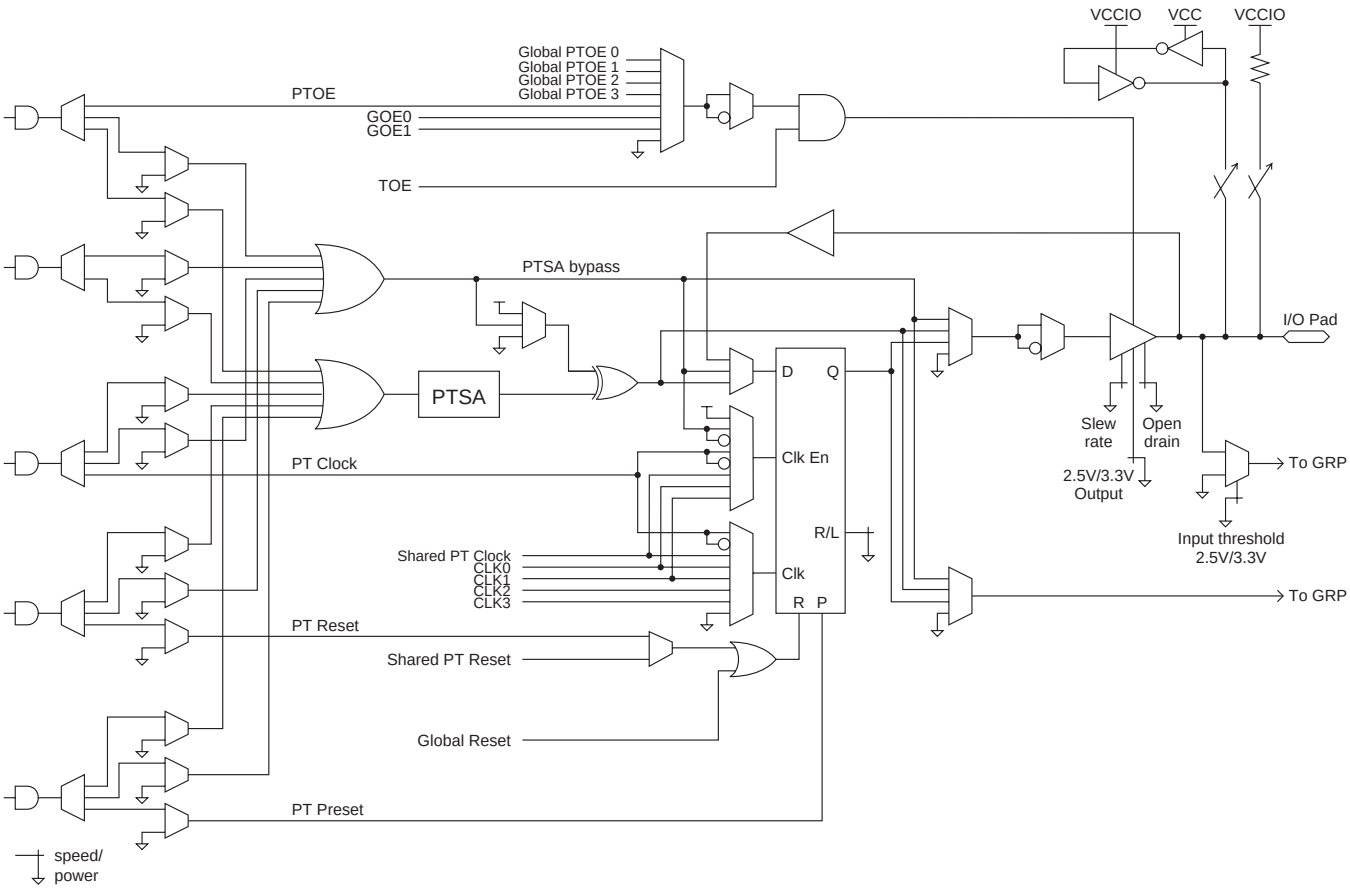


Figure 4. ispLSI 5000VE Macrocell



Note: Not all macrocells have I/O pads.

Global Clock Distribution

The ispLSI 5000VE Family has four dedicated clock input pins: CLK0 - CLK3. CLK0 input is used as the dedicated master clock that has the lowest internal clock skew with no clock inversion to maintain the fastest internal clock speed. The clock inversion is available on the remaining CLK1 - CLK3 signals. By sharing the pins with the I/O pins, CLK2 and CLK3 can not only be inverted but are also available for logic implementation through GRP signal routing. Figure 5 shows these different clock distribution options.

Figure 5. ispLSI 5000VE Global Clock Structure

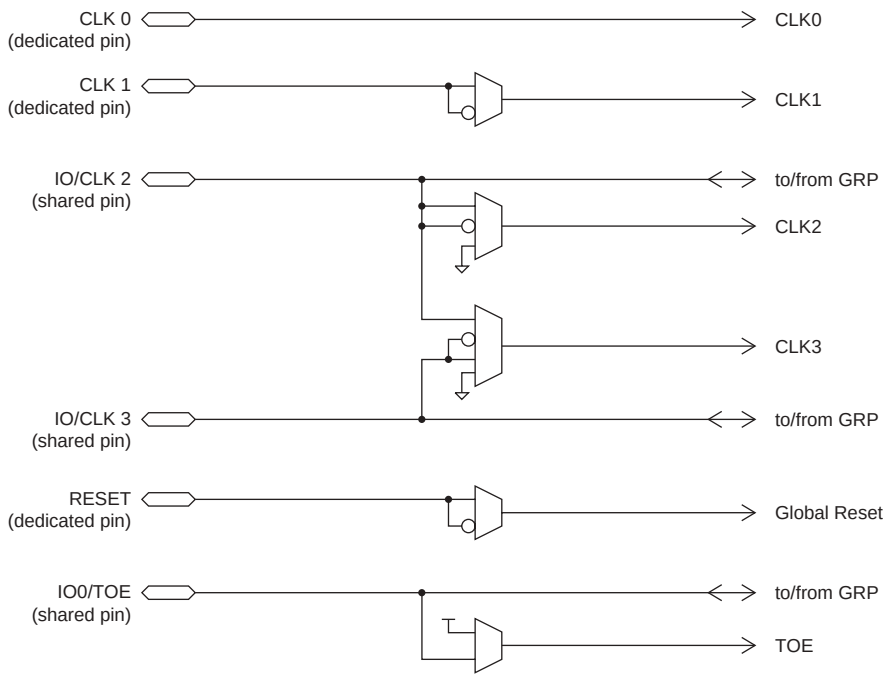


Figure 6. Boundary Scan Register Circuit for I/O Pins

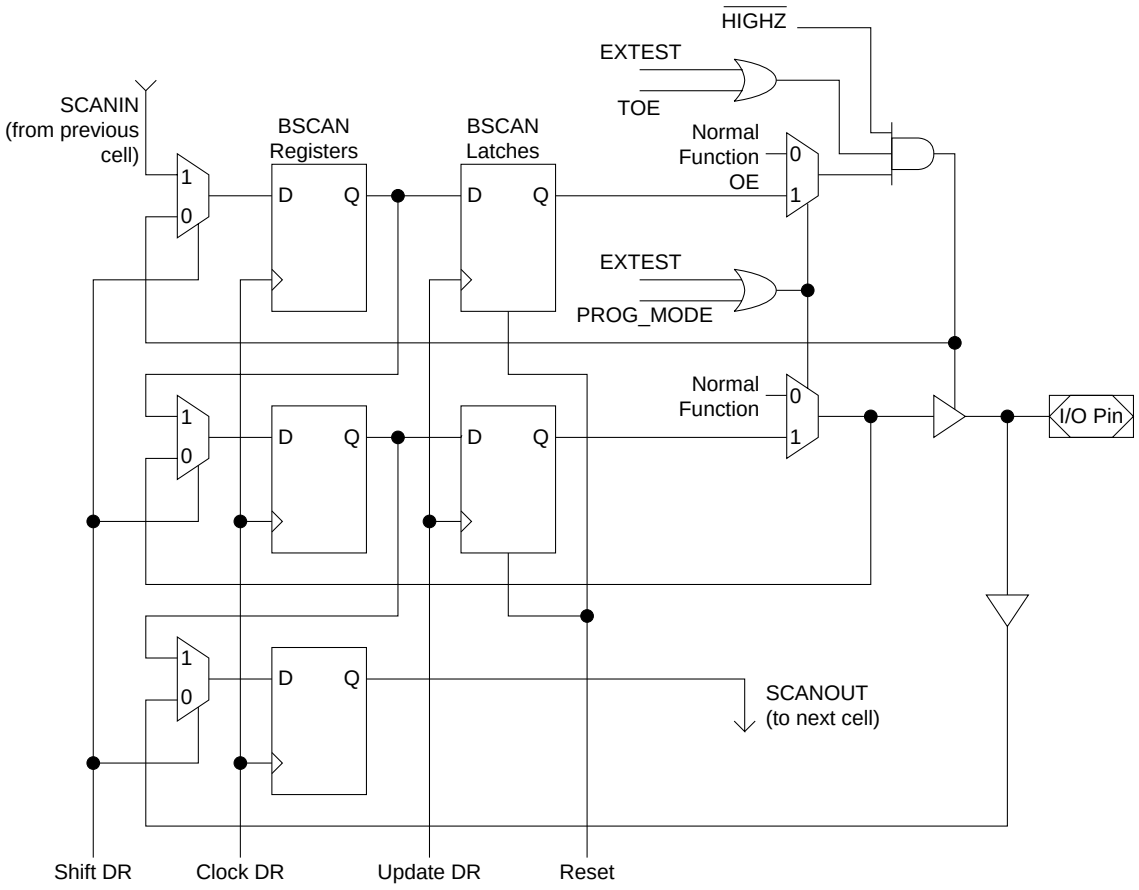


Figure 7. Boundary Scan Register Circuit for Input-Only Pins

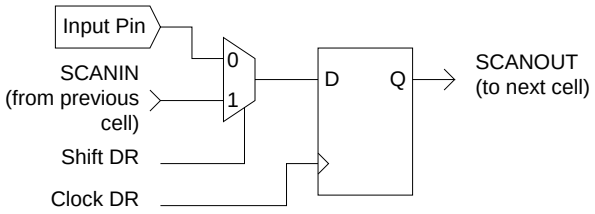
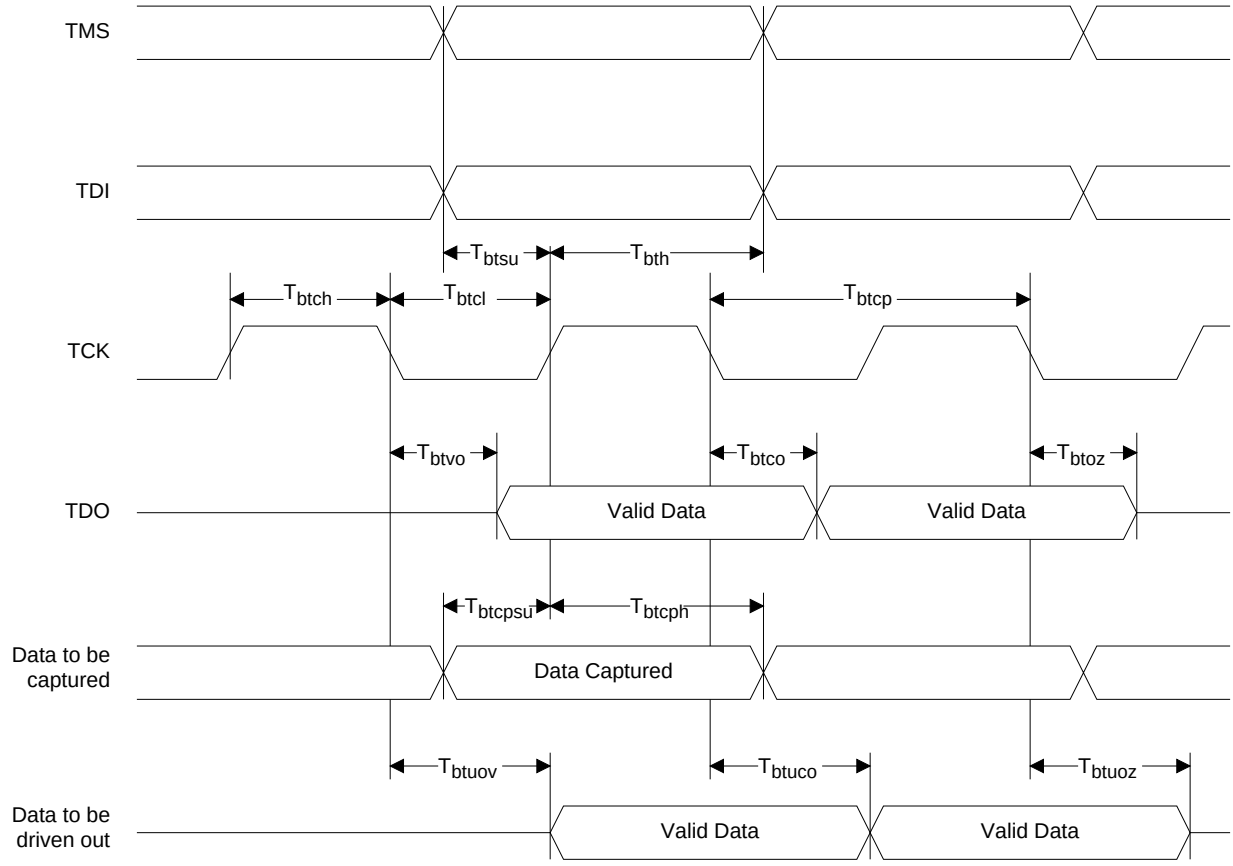


Figure 8. Boundary Scan Waveforms and Timing Specifications



SYMBOL	PARAMETER	MIN	MAX	UNITS
t_{btcp}	TCK [BSCAN test] clock pulse width	125	–	ns
t_{btch}	TCK [BSCAN test] pulse width high	62.5	–	ns
t_{btcl}	TCK [BSCAN test] pulse width low	62.5	–	ns
t_{btsu}	TCK [BSCAN test] setup time	25	–	ns
t_{bth}	TCK [BSCAN test] hold time	25	–	ns
t_{rf}	TCK [BSCAN test] rise and fall time	50	–	mV/ns
t_{btco}	TAP controller falling edge of clock to valid output	–	25	ns
t_{btoz}	TAP controller falling edge of clock to data output disable	–	25	ns
t_{btvo}	TAP controller falling edge of clock to data output enable	–	25	ns
t_{btcpsu}	BSCAN test Capture register setup time	25	–	ns
t_{btcph}	BSCAN test Capture register hold time	25	–	ns
t_{btuco}	BSCAN test Update reg, falling edge of clock to valid output	–	50	ns
t_{btuoz}	BSCAN test Update reg, falling edge of clock to output disable	–	50	ns
t_{btuov}	BSCAN test Update reg, falling edge of clock to output enable	–	50	ns

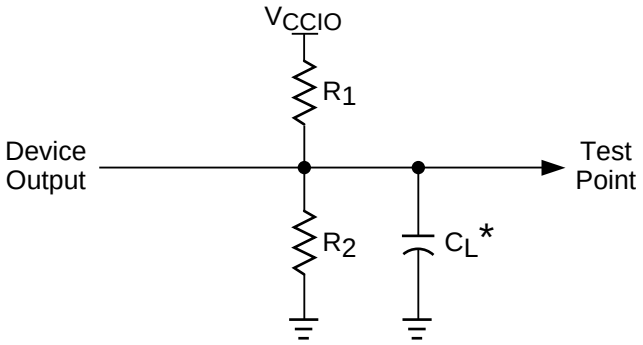
Switching Test Conditions

Input Pulse Levels	GND to $V_{CCIO_{min}}$
Input Rise and Fall Time	≤ 1.5ns 10% to 90%
Input Timing Reference Levels	1.5V
Ouput Timing Reference Levels	1.5V
Output Load	See Figure 9

Table 2-0003/5KVE

3-state levels are measured 0.5V from steady-state active level.

Figure 9. Test Load



*C_L includes Test Fixture and Probe Capacitance.

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Output Load Conditions (See Figure 9)

TEST CONDITION		3.3V R1	3.3V R2	2.5V R1	2.5V R2	CL
A		316Ω	348Ω	511Ω	475Ω	35pF
B	Active High	∞	348Ω	∞	475Ω	35pF
	Active Low	316Ω	∞	511Ω	∞	35pF
C	Active High to Z at V_{OH}-0.5V	∞	348Ω	∞	475Ω	5pF
	Active Low to Z at V_{OL}+0.5V	316Ω	∞	511Ω	∞	5pF
D	Slow Slew	∞	∞	∞	∞	35pF

Table 2-0004A/5KVE

DC Electrical Characteristics for 3.3V Range[1]

Over Recommended Operating Conditions

SYMBOL	PARAMETER	CONDITION	MIN.	TYP.	MAX.	UNITS
V_{CCIO}	I/O Reference Voltage		3.0	–	3.6	V
V_{IL}	Input Low Voltage		-0.3	–	0.8	V
V_{IH}	Input High Voltage		2.0	–	5.25	V
V_{OL}	Output Low Voltage	$V_{CCIO = min}$, I_{OL} = 8 mA	–	–	0.4	V
V_{OH}	Output High Voltage	$V_{CCIO = min}$, I_{OH} = -4 mA	2.4	–	–	V

Table 2-0007/5KVE

1. I/O voltage configuration must be set to VCC.

DC Electrical Characteristics for 2.5V Range[1]

Over Recommended Operating Conditions

SYMBOL	PARAMETER	CONDITION	MIN.	TYP.	MAX.	UNITS
V_{CCIO}	I/O Reference Voltage		2.3	–	2.7	V
V_{IL}	Input Low Voltage		-0.3	–	0.7	V
V_{IH}	Input High Voltage		1.7	–	5.25	V
V_{OL}	Output Low Voltage	$V_{CCIO=min}$, I_{OL}= 100μA	–	–	0.2	V
		$V_{CCIO=min}$, I_{OL}= 2mA	–	–	0.6	V
V_{OH}	Output High Voltage	$V_{CCIO=min}$, I_{OH}= -100μA	2.1	–	–	V
		$V_{CCIO=min}$, I_{OH}= -2mA	1.8	–	–	V

1. I/O voltage configuration must be set to VCCIO.

2.5V/5KVE

DC Electrical Characteristics

Over Recommended Operating Conditions

SYMBOL	PARAMETER	CONDITION	MIN.	TYP.	MAX.	UNITS
I_{IL}	Input or I/O Low Leakage Current	$0V \le V_{IN} \le V_{IL}$(Max.)	–	–	-10	μA
I_{IH}	Input or I/O High Leakage Current	$(V_{CCIO}-0.2)V \le V_{IN} \le V_{CCIO}$	–	–	10	μA
		$V_{CCIO} \le V_{IN} \le 5.25V$	–	–	50	μA
I_{PU}[1]	I/O Active Pullup Current	$0V \le V_{IN} \le V_{IL}$	–	–	-200	μA
I_{BHL}	Bus Hold Low Sustaining Current	$V_{IN} = V_{IL(max)}$	40	–	–	μA
I_{BHH}	Bus Hold High Sustaining Current	$V_{IN} = V_{IH(min)}$	-40	–	–	μA
I_{BHLO}	Bus Hold Low Overdrive Current	$0V \le V_{IN} \le V_{CCIO}$	–	–	550	μA
I_{BHLH}	Bus Hold High Overdrive Current	$0V \le V_{IN} \le V_{CCIO}$	–	–	-550	μA
I_{BHT}	Bus Hold Trip Points		V_{IL}	–	V_{IH}	V
I_{VCCIO}	Current Needed for V_{CCIO} Pin	All I/Os Pulled-up, (Total I/Os * I_{PUmax})	–	–	30	mA

1. Pullup is capable of pulling to a minimum voltage of V_{OH} under no-load conditions.

DC Char_5KVE

External Switching Characteristics

Over Recommended Operating Conditions

PARAM.	TEST[3] COND.	DESCRIPTION [4,5]	-165		-125		UNITS
			MIN.	MAX.	MIN.	MAX.	
tpd1[6]	A	Data Prop. Delay, 5PT Bypass	—	6.0	—	7.5	ns
tpd2[6]	A	Data Propagation Delay	—	7.5	—	9.5	ns
fmax	A	Clock Frequency with Internal Feedback[1]	165	—	125	—	MHz
fmax (Ext.)	—	Clock Freq. with Ext. Feedback,1/(tsu2 + tco1)	118	—	87	—	MHz
fmax (Tog.)	—	Clock Frequency, Max Toggle[2]	200	—	167	—	MHz
tsu1	—	GLB Reg. Setup Time before Clk, 5PT bypass	4.0	—	5.0	—	ns
tco1[6]	A	GLB Reg. Clock to Output Delay	—	3.0	—	4.5	ns
th1	—	GLB Reg. Hold Time after Clock, 5PT bypass	0.0	—	0.0	—	ns
tsu2	—	GLB Reg. Setup Time before Clock	5.5	—	7.0	—	ns
th2	—	GLB Reg. Hold Time after Clock	0.0	—	0.0	—	ns
tsu3	—	GLB Reg. Setup Time before Clock, Input Reg. Path	2.5	—	3.5	—	ns
th3	—	GLB Reg. Hold Time after Clock, Input Reg. Path	0.5	—	0.5	—	ns
tr1	A	Ext. Reset Pin to Output Delay	—	8.0	—	10.0	ns
trw1[7]	—	Ext. Reset Pulse Duration	4.0	—	5.0	—	ns
tpten/dis[6]	B/C	Local Product Term Output Enable/Disable	—	7.0	—	8.5	ns
tgpten/dis[6]	B/C	Global Product Term Output Enable/Disable	—	12.0	—	14.0	ns
tgen/dis[6]	B/C	Global OE Input to Output Enable/Disable	—	4.5	—	5.5	ns
tten/dis[6]	B/C	Test OE Input to Output Enable/Disable	—	7.5	—	10.5	ns
twh	—	Ext. Sync. Clock Pulse Duration, High	2.5	—	3.0	—	ns
twl	—	Ext. Sync. Clock Pulse Duration, Low	2.5	—	3.0	—	ns

1. Standard 16-bit counter using GRP feedback.

Timing Ext.5256ve1.eps

2. fmax (Toggle) may be less than 1/(twh + twl). This is to allow for a clock duty cycle of other than 50%.

Timing v.2.0

3. Reference Switching Test Conditions section.
4. Unless noted otherwise, all timing numbers are taken with worst case PTSA fanout, a GRP load of 1 GLB, CLK0, and high-speed AND array.
5. Timing parameters measured using normal active output driver.
6. The delay parameters are measured with Vcc as I/O voltage reference. An additional 0.5ns delay is incurred when Vccio is used as I/O voltage reference.
7. Pulse widths less than minimum may cause unknown output behavior.

External Switching Characteristics

Over Recommended Operating Conditions

PARAM.	TEST[3] COND.	DESCRIPTION [4,5]	-100		-80		UNITS
			MIN.	MAX.	MIN.	MAX.	
tpd1[6]	A	Data Prop. Delay, 5PT Bypass	—	10.0	—	12.0	ns
tpd2[6]	A	Data Propagation Delay	—	12.0	—	15.0	ns
fmax	A	Clock Frequency with Internal Feedback[1]	100	—	80	—	MHz
fmax (Ext.)	—	Clock Freq. with Ext. Feedback,1/(tsu2 + tco1)	67	—	56	—	MHz
fmax (Tog.)	—	Clock Frequency, Max Toggle[2]	125	—	100	—	MHz
tsu1	—	GLB Reg. Setup Time before Clk, 5PT bypass	7.0	—	8.0	—	ns
tco1[6]	A	GLB Reg. Clock to Output Delay	—	6.0	—	7.0	ns
th1	—	GLB Reg. Hold Time after Clock, 5PT bypass	0.0	—	0.0	—	ns
tsu2	—	GLB Reg. Setup Time before Clock	9.0	—	11.0	—	ns
th2	—	GLB Reg. Hold Time after Clock	0.0	—	0.0	—	ns
tsu3	—	GLB Reg. Setup Time before Clock, Input Reg. Path	4.5	—	5.5	—	ns
th3	—	GLB Reg. Hold Time after Clock, Input Reg. Path	1.0	—	1.0	—	ns
tr1	A	Ext. Reset Pin to Output Delay	—	11.5	—	13.0	ns
trw1[7]	—	Ext. Reset Pulse Duration	6.5	—	8.0	—	ns
tpten/dis[6]	B/C	Local Product Term Output Enable/Disable	—	10.0	—	12.0	ns
tgpten/dis[6]	B/C	Global Product Term Output Enable/Disable	—	15.5	—	17.0	ns
tgen/dis[6]	B/C	Global OE Input to Output Enable/Disable	—	7.5	—	9.0	ns
tten/dis[6]	B/C	Test OE Input to Output Enable/Disable	—	11.5	—	12.5	ns
twh	—	Ext. Sync. Clock Pulse Duration, High	4.0	—	5.0	—	ns
twl	—	Ext. Sync. Clock Pulse Duration, Low	4.0	—	5.0	—	ns

1. Standard 16-bit counter using GRP feedback.

Timing Ext.5256ve2.eps

2. fmax (Toggle) may be less than 1/(twh + twl). This is to allow for a clock duty cycle of other than 50%.

Timing v.2.0

3. Reference Switching Test Conditions section.
4. Unless noted otherwise, all timing numbers are taken with worst case PTSA fanout, a GRP load of 1 GLB, CLK0, and high-speed AND array.
5. Timing parameters measured using normal active output driver.
6. The delay parameters are measured with Vcc as I/O voltage reference. An additional 0.5ns delay is incurred when Vccio is used as I/O reference.
7. Pulse widths less than minimum may cause unknown output behavior.
   used as I/O voltage reference.

Internal Timing Parameters

Over Recommended Operating Conditions

PARAMETER	DESCRIPTION	-165		-125		-100		-80		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
In/Out Delays										
tin	Input Buffer Delay	–	0.6	–	1.3	–	2.3	–	2.3	ns
tgclk_in	Global Clock Buffer Input Delay (clk0)	–	0.7	–	1.3	–	1.8	–	1.8	ns
trst	Global Reset Pin Delay	–	4.9	–	6.6	–	7.1	–	7.1	ns
tgoe	Global OE Pin Delay	–	3.2	–	3.9	–	5.9	–	7.4	ns
tbuf	Output Buffer Delay	–	1.9	–	2.2	–	2.7	–	3.7	ns
ten	Output Enable Delay	–	1.3	–	1.6	–	1.6	–	1.6	ns
tdis	Output Disable Delay	–	1.3	–	1.6	–	1.6	–	1.6	ns
Routing/GLB Delays										
troute	GRP and Logic Delay	–	3.2	–	3.6	–	4.0	–	4.5	ns
tpdb	5-pt Bypass Propagation Delay	–	0.3	–	0.4	–	1.0	–	1.5	ns
tpdi	Combinatorial Propagation Delay	–	0.0	–	0.0	–	0.0	–	0.0	ns
tptsa	Product Term Sharing Array	–	1.8	–	2.4	–	3.0	–	4.5	ns
tfbk	Internal Feedback Delay	–	0.0	–	0.0	–	0.0	–	0.5	ns
tinreg	Input Buffer to Macrocell Register Delay	–	2.0	–	2.5	–	2.5	–	3.5	ns
Register/Latch Delays										
ts	Register Setup Time	0.6	–	1.0	–	1.5	–	1.5	–	ns
ts_pt	Register Setup Time (Product Term Clock)	0.6	–	1.0	–	1.5	–	1.5	–	ns
th	Register Hold Time	2.4	–	3.0	–	4.0	–	5.0	–	ns
tcoi	Register Clock to GLB Output Delay	–	0.4	–	1.0	–	1.5	–	1.5	ns
tsl	Latch Setup Time	0.6	–	1.0	–	1.5	–	1.5	–	ns
thl	Latch Hold Time	2.4	–	3.0	–	4.0	–	5.0	–	ns
tgoi	Latch Gate to GLB Output Delay	–	0.4	–	1.0	–	1.5	–	1.5	ns
tpdli	GLB Latch propagation Delay	–	1.0	–	1.5	–	2.0	–	2.5	ns
tces	Clock Enable Setup Time	4.1	–	4.3	–	5.3	–	6.3	–	ns
tceh	Clock Enable Hold Time	0.9	–	1.7	–	2.7	–	3.7	–	ns
tsri	Asynchronous Set/Reset to GLB Output Delay	–	1.2	–	1.2	–	1.7	–	2.2	ns
tsrr	Asynchronous Set/Reset Recovery Time	0.8	–	1.2	–	1.2	–	2.2	–	ns
Control Delays										
tptclk	Macrocell PT Clock Delay	–	0.4	–	0.4	–	0.5	–	0.5	ns
tbclk	Block PT Clock Delay	–	1.4	–	1.9	–	2.5	–	2.5	ns
tptsr	Macrocell PT Set/Reset Delay	–	2.1	–	3.7	–	4.8	–	4.8	ns
tbsr	Block PT Set/Reset Delay	–	3.1	–	5.7	–	6.8	–	6.8	ns
tptoe	Macrocell PT OE Delay	–	1.9	–	2.0	–	2.1	–	3.6	ns
tgptoe	Global PT OE Delay	–	6.9	–	7.5	–	7.6	–	8.6	ns

Note: Internal Timing Parameters are not tested and are for reference only. Refer to Timing Model in this data sheet for further details.

Timing v.2.0

ispLSI 5256VE Timing Parameters (continued)

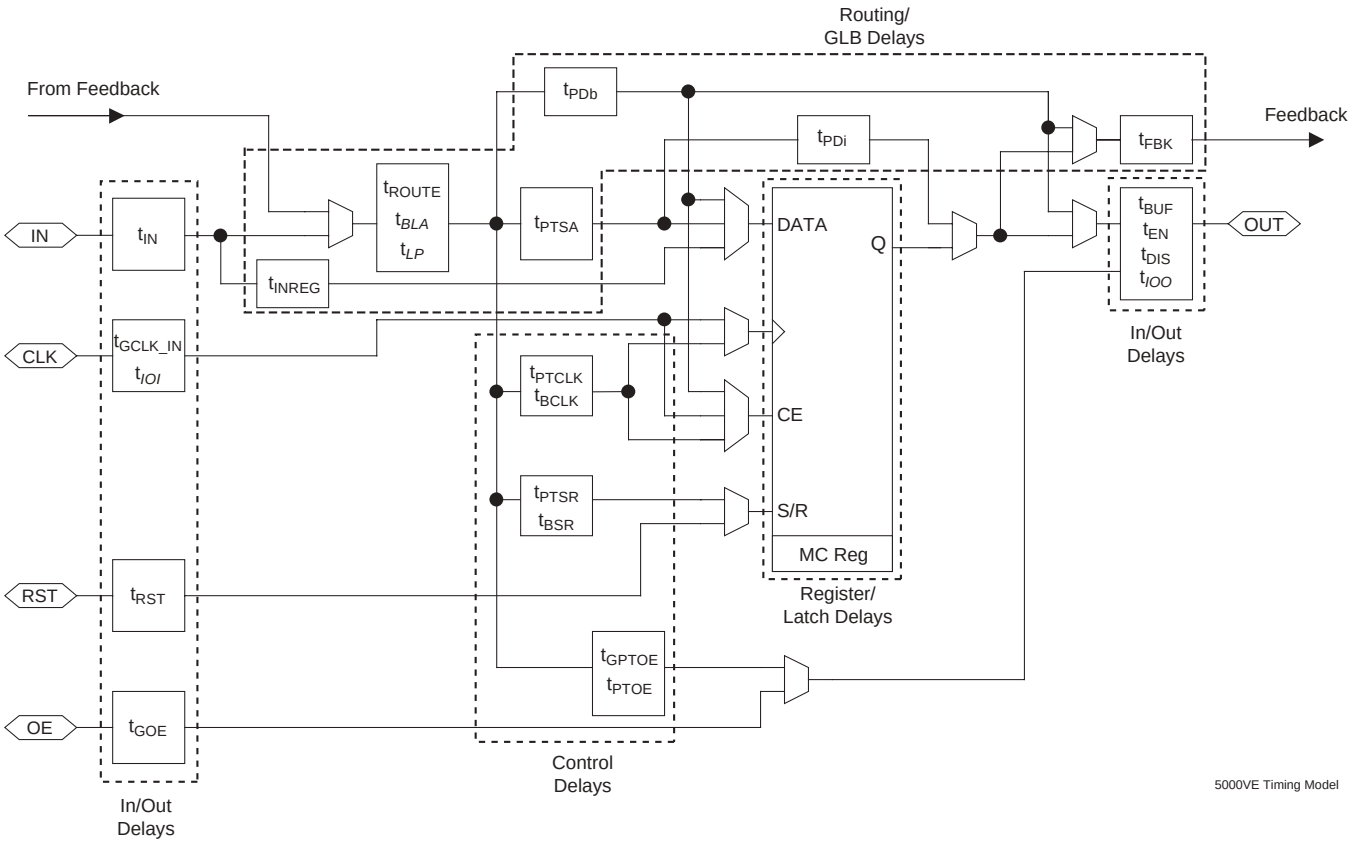
ADDER TYPE	BASE PARAMETER	ADDER				UNITS
		-165	-125	-100	-80	
Routing Adders						
tlp	**t**route	1.0	1.5	1.5	1.5	ns
Tioi Input Adders						
clk1	**t**gclk_in	1.4	1.7	1.7	1.7	ns
clk2	**t**gclk_in	1.4	1.7	1.7	1.7	ns
clk3	**t**gclk_in	1.4	1.7	1.7	1.7	ns
Tioo Output Adders[1]						
Slow Slew I/O	**t**buf, **t**en	4.0	4.0	4.0	4.0	ns
LVTTL_out	**t**buf, **t**en, **t**dis	0.0	0.0	0.0	0.0	ns
LVCMOS25_out	**t**buf, **t**en, **t**dis	0.5	0.5	0.5	0.5	ns
LVCMOS33_out	**t**buf, **t**en, **t**dis	0.0	0.0	0.0	0.0	ns
Tbla Additional Block Loading Adders						
1	**t**route	0.1	0.1	0.1	0.1	ns
2	**t**route	0.1	0.2	0.2	0.2	ns
3	**t**route	0.2	0.3	0.3	0.3	ns
4	**t**route	0.3	0.4	0.4	0.4	ns
5	**t**route	0.4	0.5	0.5	0.5	ns
6	**t**route	0.4	0.6	0.6	0.6	ns
7	**t**route	0.5	0.7	0.7	0.7	ns

[1]Timing for open drain configurations is the same as non-open drain configurations.

Timing Table/5256VE
Timing v.2.0

Note: Internal Timing Parameters are not tested and are for reference only. Refer to Timing Model in this data sheet for details.

ispLSI 5256VE Timing Model



Note: Italicized parameters are delay adders above and beyond default conditions (i.e. GRP load of one GLB, CLK0, high-speed AND Array and VCC I/O option).

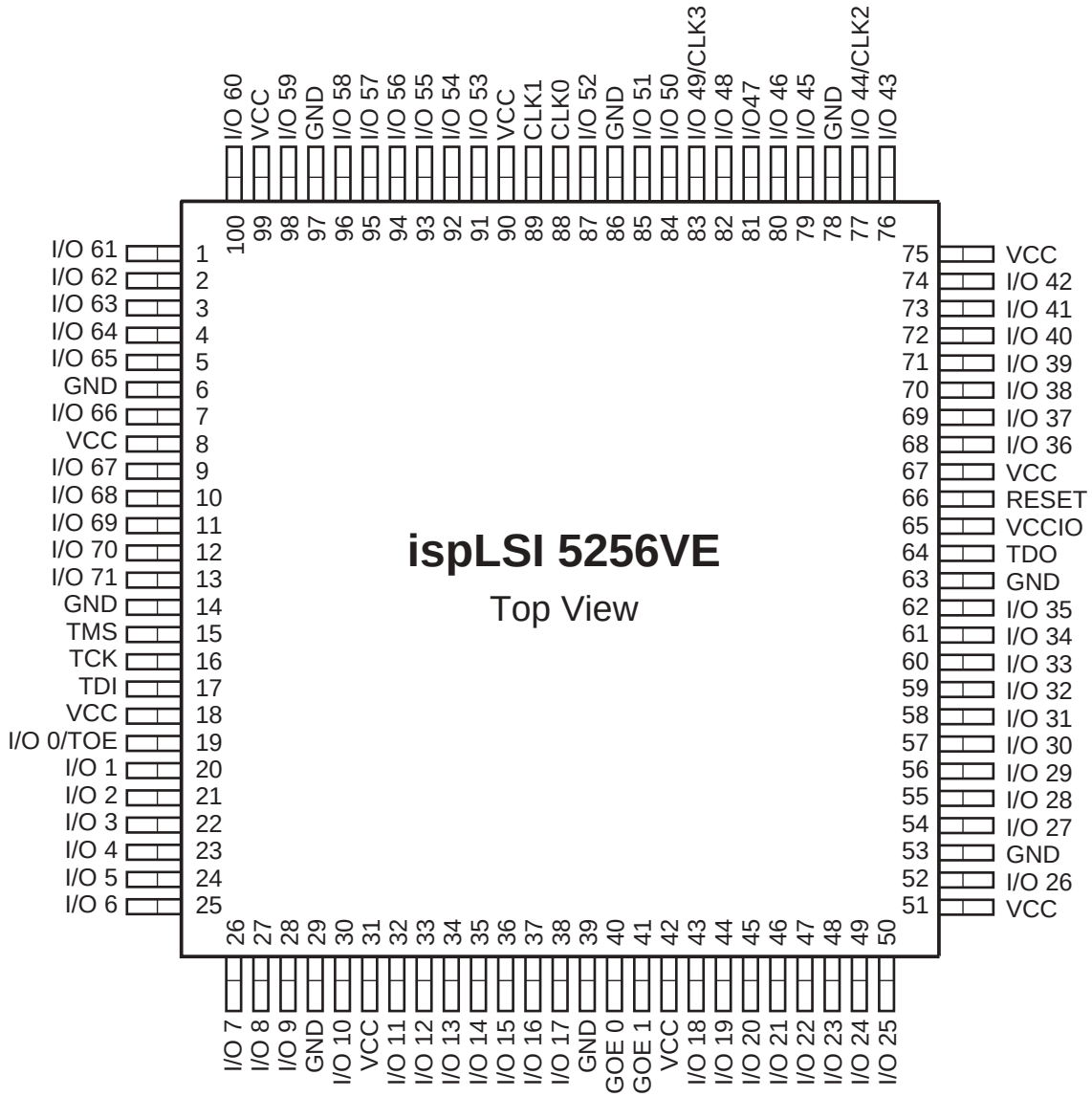
Signal Descriptions

Signal Name	Description
TMS	Input - This pin is the Test Mode Select input, which is used to control the JTAG state machine.
TCK	Input - This pin is the Test Clock input pin used to clock through the JTAG state machine.
TDI	Input - This pin is the JTAG Test Data In pin used to load data.
TDO	Output - This pin is the JTAG Test Data Out pin used to shift data out.
TOE / I/O0	Input/Output - This pin functions as either the Test Output Enable pin or an I/O pin based upon customer's design. TOE tristates all I/O pins when a logic low is driven.
GOE0, GOE1	Input - These two pins are the Global Output Enable input pins.
RESET	Dedicated Reset Input - This pin resets all registers in the device. The global polarity (active high or low input) for this pin is selectable.
I/O	Input/Output – These are the general purpose I/O used by the logic array.
GND	Ground
NC[1]	No connect.
VCC	Vcc
CLK0, CLK1	Dedicated clock inputs for all registers. Both clocks are muxed before being used as the clock input to all registers in the device.
CLK2 / I/O, CLK3 / I/O	Input/Output - These pins share functionality. They can be used as dedicated clock inputs for all registers, as well as I/O pins.
VCCIO	Input - This pin is used for optional 2.5V outputs. Every I/O can independently select either 3.3V or the optional voltage as its output level. If the optional output voltage is not required, this pin must be connected to the Vcc supply. Programmable pull-up resistors and bus-hold latches only draw current from this supply.

1. NC pins are not to be connected to any active signals, VCC or GND.

Pin Configuration

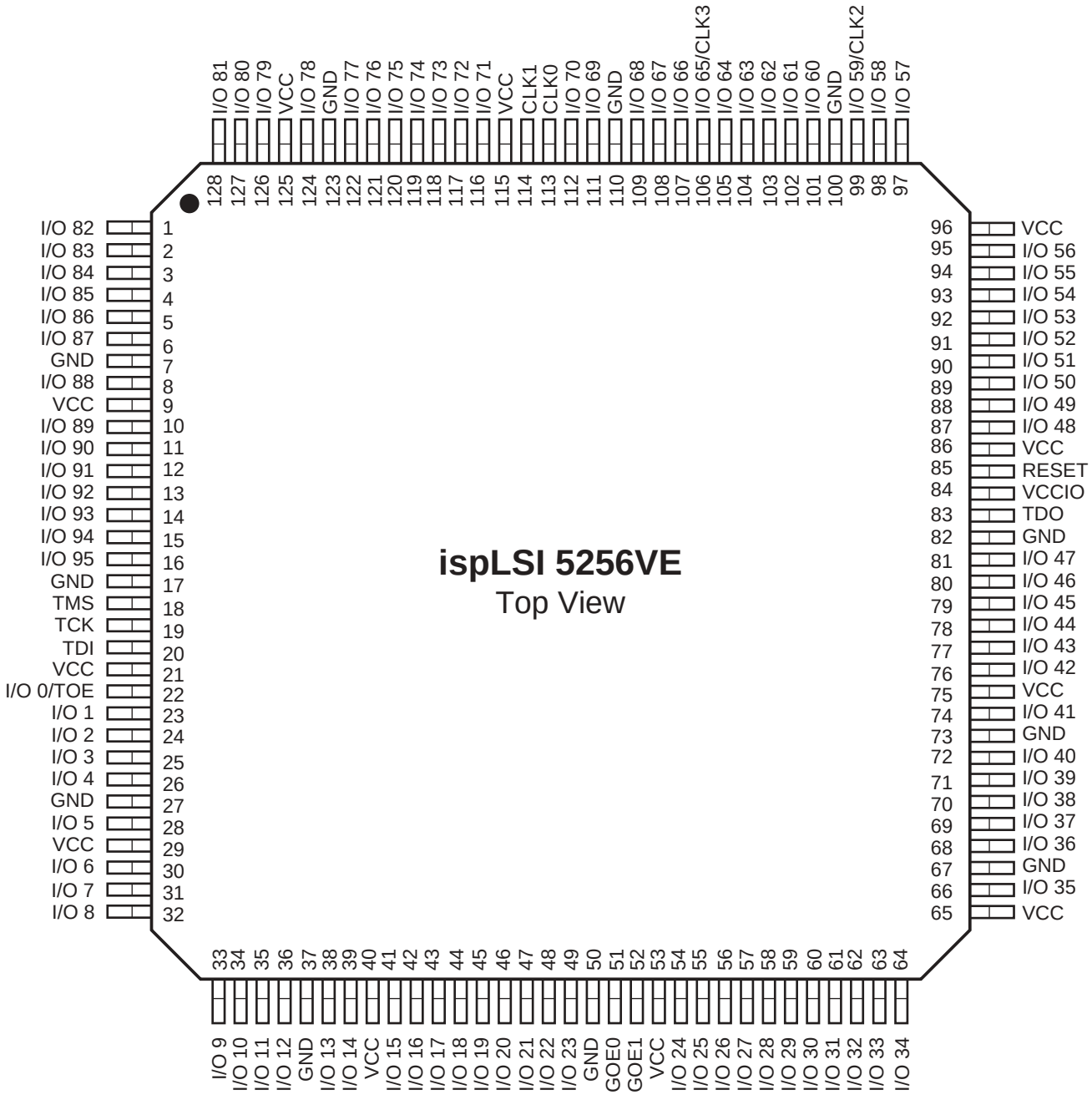
ispLSI 5256VE 100-Pin TQFP (0.5mm Lead Pitch / 14.0mm x 14.0mm Body Size)



100 TQFP/5256VE

Pin Configuration

ispLSI 5256VE 128-Pin TQFP (0.4mm Lead Pitch / 14.0mm x 14.0mm Body Size)



128 TQFP/5256VE

Signal Configuration

ispLSI 5256VE 272-Ball BGA (1.27mm Ball Pitch / 27.0mm x 27.0mm Body Size)

	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	
A	I/O 114	I/O 115	I/O 119/ CLK2	NC[1]	NC[1]	I/O 126	I/O 129	I/O 132	I/O 136	I/O 139	I/O 140	NC[1]	NC[1]	I/O 149	I/O 151	NC[1]	NC[1]	I/O 160	I/O 164	GND	A
B	NC[1]	NC[1]	NC[1]	I/O 116	I/O 121	I/O 125	I/O 128	I/O 131/ CLK3	I/O 135	NC[1]	I/O 141	I/O 143	I/O 147	NC[1]	I/O 153	I/O 157	I/O 159	NC[1]	I/O 163	I/O 165	B
C	I/O 111	NC[1]	NC[1]	I/O 117	I/O 120	I/O 123	NC[1]	NC[1]	NC[1]	I/O 138	CLK0	I/O 144	I/O 148	I/O 152	I/O 156	NC[1]	NC[1]	NC[1]	NC[1]	I/O 169	C
D	I/O 109	NC[1]	I/O 113	GND	NC[1]	VCC	I/O 124	GND	I/O 133	VCC	CLK1	I/O 145	GND	I/O 155	VCC	I/O 161	GND	NC[1]	I/O 167	NC[1]	D
E	I/O 105	I/O 108	NC[1]	NC[1]													I/O 168	I/O 171	NC[1]	I/O 172	E
F	I/O 102	I/O 104	NC[1]	VCC													VCC	I/O 173	I/O 175	I/O 176	F
G	I/O 100	I/O 101	NC[1]	I/O 106													NC[1]	I/O 177	NC[1]	I/O 179	G
H	I/O 97	I/O 98	NC[1]	GND													GND	I/O 180	I/O 181	NC[1]	H
J	TDO	VCCIO	RESET	I/O 96													I/O 183	I/O 184	I/O 185	NC[1]	J
K	I/O 92	I/O 93	I/O 94	NC[1]													VCC	I/O 188	I/O 187	NC[1]	K
L	NC[1]	I/O 89	I/O 90	VCC													TCK	TMS	I/O 191	I/O 190	L
M	I/O 88	NC[1]	I/O 86	I/O 85													I/O 2	I/O 1	I/O 0/ TOE	TDI	M
N	I/O 84	NC[1]	I/O 82	GND													GND	I/O 5	I/O 4	NC[1]	N
P	I/O 81	NC[1]	I/O 80	I/O 77													I/O 12	I/O 9	NC[1]	I/O 6	P
R	NC[1]	I/O 78	I/O 76	VCC													VCC	NC[1]	NC[1]	I/O 8	R
T	NC[1]	NC[1]	I/O 74	NC[1]													NC[1]	I/O 14	I/O 13	I/O 11	T
U	I/O 73	I/O 70	NC[1]	GND	I/O 64	VCC	I/O 58	GND	I/O 48	GOE1	VCC	I/O 37	GND	I/O 28	VCC	I/O 21	GND	NC[1]	NC[1]	NC[1]	U
V	I/O 72	I/O 69	NC[1]	I/O 65	I/O 62	NC[1]	NC[1]	NC[1]	NC[1]	GOE0	I/O 42	I/O 38	I/O 34	NC[1]	NC[1]	I/O 24	I/O 20	I/O 17	I/O 16	NC[1]	V
W	NC[1]	NC[1]	I/O 66	NC[1]	I/O 60	I/O 56	I/O 53	I/O 50	I/O 46	I/O 45	I/O 41	NC[1]	NC[1]	I/O 32	I/O 29	I/O 25	NC[1]	NC[1]	NC[1]	NC[1]	W
Y	NC[1]	I/O 67	NC[1]	I/O 61	I/O 57	I/O 54	I/O 52	I/O 49	NC[1]	I/O 44	NC[1]	I/O 40	I/O 36	I/O 33	I/O 30	I/O 26	NC[1]	I/O 22	NC[1]	I/O 18	Y
	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	

ispLSI 5256VE

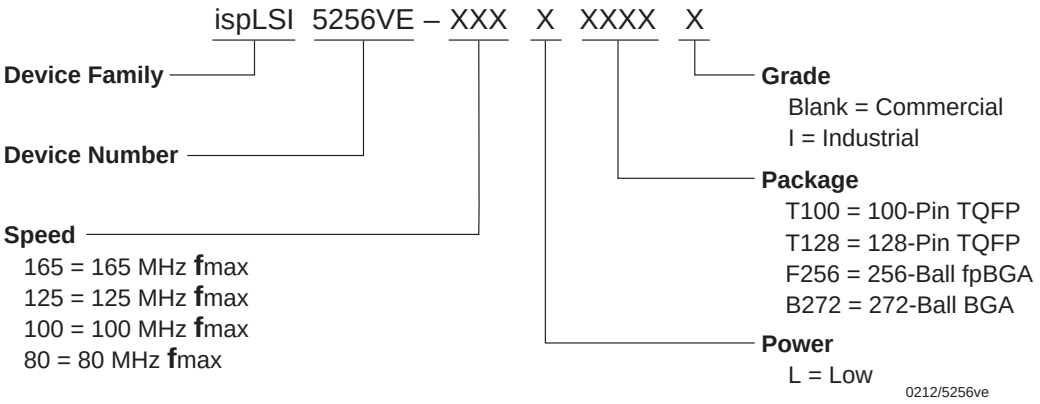
Bottom View

GND	GND	GND	GND
GND	GND	GND	GND
GND	GND	GND	GND
GND	GND	GND	GND

1. NCs are not to be connected to any active signals, Vcc or GND.

Note: Ball A1 indicator dot on top side of package.

Part Number Description



Ordering Information

COMMERCIAL

FAMILY	fmax (MHz)	tpd (ns)	ORDERING NUMBER	PACKAGE
ispLSI	165	6.0	ispLSI 5256VE-165LT100	100-Pin TQFP
	165	6.0	ispLSI 5256VE-165LT128	128-Pin TQFP
	165	6.0	ispLSI 5256VE-165LF256	256-Ball fpBGA
	165	6.0	ispLSI 5256VE-165LB272	272-Ball BGA
	125	7.5	ispLSI 5256VE-125LT100	100-Pin TQFP
	125	7.5	ispLSI 5256VE-125LT128	128-Pin TQFP
	125	7.5	ispLSI 5256VE-125LF256	256-Ball fpBGA
	125	7.5	ispLSI 5256VE-125LB272	272-Ball BGA
	100	10	ispLSI 5256VE-100LT100	100-Pin TQFP
	100	10	ispLSI 5256VE-100LT128	128-Pin TQFP
	100	10	ispLSI 5256VE-100LF256	256-Ball fpBGA
	100	10	ispLSI 5256VE-100LB272	272-Ball BGA

Table 2-0041A/5256VE

INDUSTRIAL

FAMILY	fmax (MHz)	tpd (ns)	ORDERING NUMBER	PACKAGE
ispLSI	125	7.5	ispLSI 5256VE-125LT100I	100-Pin TQFP
	125	7.5	ispLSI 5256VE-125LT128I	128-Pin TQFP
	125	7.5	ispLSI 5256VE-125LF256I	256-Ball fpBGA
	125	7.5	ispLSI 5256VE-125LB272I	272-Ball BGA
	100	10	ispLSI 5256VE-100LT100I	100-Pin TQFP
	100	10	ispLSI 5256VE-100LT128I	128-Pin TQFP
	100	10	ispLSI 5256VE-100LF256I	256-Ball fpBGA
	100	10	ispLSI 5256VE-100LB272I	272-Ball BGA
	80	12	ispLSI 5256VE-80LT100I	100-Pin TQFP
	80	12	ispLSI 5256VE-80LT128I	128-Pin TQFP
	80	12	ispLSI 5256VE-80LF256I	256-Ball fpBGA
	80	12	ispLSI 5256VE-80LB272I	272-Ball BGA

The ispLSI 5256VE is dual-marked with both Commercial and Industrial grades. The Commercial speed grade is faster (i.e. ispLSI 5256VE-165LF256) than the Industrial speed grade (i.e. ispLSI 5256VE-125LF256I).

Table 2-0041B/5256VE